

Mixed-Signal Test System KT-7500 FINN



Overview:

The test system KT-7500 FINN is a high performance, mixed-signal test system with real-time engine and asynchronous FPGA-sequencer for development, characterization, production and application lab. The scalable architecture is based on the PXI industry standard with the ABEx system extension. Depending on the population of the chassis it allows single and/or parallel test of mixed-signal devices.

Highlights:

- Modular Platform Based on PXI and ABex
- Configurable as digital, analog, mixed-signal tester
- Universal pin: digital I/O, analog I/O, DPS
- PMU per pin architecture
- FPGA real-time engine per pin electronic
- High Voltage PMU +/- 100V
- Digitizer up to 100MS/s 14-bit
- AWG up to 100MS/s 16-bit
- Expandable with standard PXI modules

Field of Applications:

- Development
- Characterization
- Productions test (wafer-sort and final)
- Applications lab

Target Devices:

- Medium Pincount Digital Devices
- Analog Devices
- Medium Pincount Mixed Signal Devices
- Smartcards
- MEMS
- Sensors



The KT7500 FINN is a flexible, configurable test platform and offers solutions for various test requirements. To meet the concerns of increasing shorter life spans of devices and to match the fast requirements changes, the KT-7500 is based on standard PXI technology with a wide range of standard- and application specific modules.

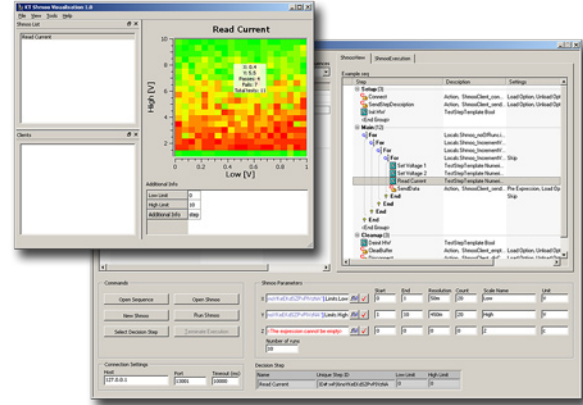
The KT-7500 has a very small footprint and can be completely integrated in a manipulator to dock directly on probers or device handlers. Even as table top system the required space is not much more than used for a signal analyzer.

The fully asynchronous tester can be used for testing medium pincount Digital Devices, Analog Devices, medium pincount Mixed Signal Devices as well as Smartcards, MEMS and other Sensors.

In a configuration with our dedicated RF Terminal Modules, the KT-7500 FINN is a high parallel protocol tester for RF-ID devices. These protocol tests can be executed within a few milliseconds for up to 64 devices in parallel without overhead.

Software:

- Windows based operating system
- Using National Instruments TestStand and LabVIEW
- Shmoo plots
- Applications specific programming service available
- Customization of GUI and Tools possible



System Components:

Instrumentation Platform:

- o ABEx® Chassis
- o PXI Chassis (8, 14 or 18 Slots)
- o Host PC for editing and visualization

KT Instruments:

- o DIG5010 ± 12V, 200mA Universal Pin Electronic
- o Source Measurement Unit
- o Parametric Measurement Unit
- o Scopes
- o Digital Pins
- o Generators
- o others on request

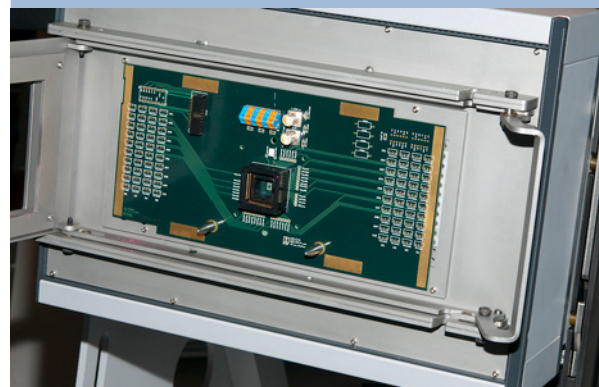
Options:

- o Flexible ABEx-Cart
- o Family-Board Adapter ABEx-Connect



- o Pogo tower integration

Interface to mount test adapters for family boards, handlers and prober interface boards.



Family board adapter example.